

4th IEEE Latin-American Test Workshop
LATW2003



Natal, Brazil
February 16-19, 2003

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Call for Papers

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The IEEE Latin-American Test Workshop provides an annual forum for test and fault tolerance professionals and technologists from Latin America and all over the world, to present and discuss various aspects of system, board and component testing and fault-tolerance with design, manufacturing and field considerations in mind. The best papers of the workshop will be invited to be re-submitted for a special issue of the **Journal of Electronic Testing: Theory and Applications (JETTA)**, published by **Kluwer Academic Publishers**.

Topics of interest include but are not limited to:

- Analog and Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect and Failure Analysis
- Dependability Estimation
- Design and Synthesis for Testability
- Design Verification/Validation
- E-Beam and Thermal Testing
- Economics of Test
- Fault Modeling and Simulation
- Fault Injection and Diagnosis
- Fault-Tolerance in Hardware/Software
- Fault-Tolerant Architectures
- IDDQ Test
- On-Line Testing
- Process Control and Measurements
- Radiation Hardening Techniques
- Software Testing/Software Design for Test
- System-on-Chip Test
- Yield Learning and Enhancement

Paper Submission Information:

To encourage and facilitate informal discussion, participation will be limited. Those interested in presenting recent results at the workshop are invited to submit either an extended abstract, one to three pages long, or a full length paper. Post-Script or PDF electronic submissions **via the workshop web page are strongly recommended**.

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Authors should send papers in the IEEE format with a cover letter indicating the complete mail address, phone/fax numbers and e-mail addresses, the contact person and the presenter. Detailed instructions are available at the workshop web page. The Program Committee also welcomes proposals for panels and special topic sessions. For additional information please contact one of the Program Chairs.

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Submission Deadline: November 8th, 2002

Notification of Acceptance: December 13th, 2002

Camera Ready: January 10th, 2003

LATW2003 will be held in **Natal**, the capital city of Rio Grande do Norte state, located at the heart of the hospitable and pleasant Brazilian Northeast region. **Natal** is a peaceful city surrounded by dozens of **wonderful sandy beaches**: Ponta Negra and Praia do Forte in the city itself, Pipa, Pirangi, Jacumã, Maracajaú, Galinhos and many others. Buggy riders can take you to discover these beaches and also the **famous Natal's dunes**, specially those located at Genipabu. Since the sun shines for more than 300 days a year in this region, all along the Potiguar Coast the **luke-warm ocean** invites you to go swimming. All these reasons, associated to a very good infrastructure for visitors, make **Natal** a favorite touristic destination providing a great environment for holding conferences and meetings. For further information look at <http://www.turismorn.com.br>.

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